

Zhiqiang You

List of Publications by Year in descending order

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12
papers

140
citations

1478505

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1281871

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times ranked

106
citing authors

#	ARTICLE	IF	CITATIONS
1	A high-performance CNN method for offline handwritten Chinese character recognition and visualization. <i>Soft Computing</i> , 2020, 24, 7977-7987.	3.6	46
2	Efficient March test algorithm for 1T1R crossbar with complete fault coverage. <i>Electronics Letters</i> , 2016, 52, 1520-1522.	1.0	20
3	Fault Modeling and Efficient Testing of Memristor-Based Memory. <i>IEEE Transactions on Circuits and Systems I: Regular Papers</i> , 2021, 68, 4444-4455.	5.4	16
4	Logic operation-based Design for Testability method and parallel test algorithm for 1T1R crossbar. <i>Electronics Letters</i> , 2017, 53, 1631-1632.	1.0	11
5	Logic operation-based DFT method and 1R memristive crossbar March-like test algorithm. <i>IEICE Electronics Express</i> , 2015, 12, 20150839-20150839.	0.8	9
6	A novel memristor-based restricted Boltzmann machine for contrastive divergence. <i>IEICE Electronics Express</i> , 2018, 15, 20171062-20171062.	0.8	7
7	An adaptive neural network A/D converter based on CMOS/memristor hybrid design. <i>IEICE Electronics Express</i> , 2014, 11, 20141012-20141012.	0.8	6
8	Defect Analysis and Parallel Testing for 3D Hybrid CMOS-Memristor Memory. <i>IEEE Transactions on Emerging Topics in Computing</i> , 2021, 9, 745-758.	4.6	6
9	A signal degradation reduction method for memristor ratioed logic (MRL) gates. <i>IEICE Electronics Express</i> , 2015, 12, 20150062-20150062.	0.8	5
10	A parallel-SSHI rectifier for ultra-low-voltage piezoelectric vibration energy harvesting. <i>IEICE Electronics Express</i> , 2016, 13, 20160539-20160539.	0.8	5
11	Defect Analysis and Parallel March Test Algorithm for 3D Hybrid CMOS-Memristor Memory. , 2018, , .		5
12	Integrating Two Logics Into One Crossbar Array for Logic Gate Design. <i>IEEE Transactions on Circuits and Systems II: Express Briefs</i> , 2021, 68, 2987-2991.	3.0	4